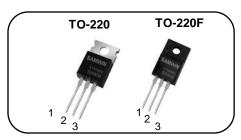


N-channel Enhanced mode TO-220/TO-220F MOSFET

Features

- High ruggedness
- Low R_{DS(ON)} (Typ1.4 Ω)@V_{GS}=10V
 Low Gate Charge (Typ 30nC)
- Improved dv/dt Capability
- 100% Avalanche Tested
- Application: DC-DC , LED , PC power



1. Gate 2. Drain 3. Source

BV_{DSS}: 500V : 5.5A $R_{DS(ON)}: 1.4\Omega$

General Description

This power MOSFET is produced with advanced technology of SAMWIN. This technology enable the power MOSFET to have better characteristics, including fast switching time, low on resistance, low gate charge and especially excellent avalanche characteristics.





Order Codes

Item	Sales Type	Marking	Package	Packaging
1	SW P 830	SW830	TO-220	TUBE
2	SW F 830	SW830	TO-220F	TUBE

Absolute maximum ratings

Symbol	Parameter		Value		
			TO-220	TO-220F	Unit
V _{DSS}	Drain to source voltage		500		V
	Continuous drain current (@T _C =25°C)		5.5*		Α
l _D	Continuous drain current (@T _C =100°C)		3.	3.8*	
I _{DM}	Drain current pulsed (note 1)		22		А
V _{GS}	Gate to source voltage		±30		V
E _{AS}	Single pulsed avalanche energy	nergy (note 2) 240		mJ	
E _{AR}	Repetitive avalanche energy (note 1)		16		mJ
dv/dt	Peak diode recovery dv/dt (note 3)		3		V/ns
	Total power dissipation (@T _C =25°C)		135	39	W
P _D	Derating factor above 25°C		1.08	0.31	W/°C
T _{STG} , T _J	Operating junction temperature & storage temperature		-55 ~ + 150		°C
T _L	Maximum lead temperature for soldering purpose, 1/8 from case for 5 seconds.		300		°C

^{*.} Drain current is limited by junction temperature.

Thermal characteristics

Symbol	Parameter	Va	Unit	
		TO-220	TO-220F	01
R _{thjc}	Thermal resistance, Junction to case	0.92	3.16	°C/W
R _{thja}	Thermal resistance, Junction to ambient	65	65	°C/W



Electrical characteristic ($T_C = 25^{\circ}C$ unless otherwise specified)

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
Off charac	teristics			•	•	•
BV _{DSS}	Drain to source breakdown voltage	V _{GS} =0V, I _D =250uA	500			V
ΔBV _{DSS} /ΔT _J	Breakdown voltage temperature coefficient	I _D =250uA, referenced to 25°C		0.48		V/ºC
	Drain to source leakage current	V _{DS} =500V, V _{GS} =0V			1	uA
I _{DSS}		V _{DS} =400V, T _C =125°C			10	uA
	Gate to source leakage current, forward	V _{GS} =30V, V _{DS} =0V	(1	(2)	100	nA
I_{GSS}	Gate to source leakage current, reverse	V _{GS} =-30V, V _{DS} =0V			-100	nA
On charac	teristics	0.4				
V _{GS(TH)}	Gate threshold voltage	V _{DS} =V _{GS} , I _D =250uA	2.0		4.0	V
R _{DS(ON)}	Drain to source on state resistance	V _{GS} =10V, I _D = 2.75A		1.4	1.5	Ω
G_fs	Forward transconductance	V_{DS} =40V, I_{D} = 2.75 A		3.2		S
Dynamic c	haracteristics		1			_
C _{iss}	Input capacitance			756		
C _{oss}	Output capacitance	V_{GS} =0V, V_{DS} =25V, f=1MHz		96		pF
C _{rss}	Reverse transfer capacitance			35		
t _{d(on)}	Turn on delay time			12		
t _r	Rising time	V_{DS} =250V, I $_{D}$ =5.5A, V_{GS} =10V, R_{G} =25 Ω (note 4,5)		33		- ns
$t_{d(off)}$	Turn off delay time			97		
t _f	Fall time			48		
Q_g	Total gate charge	., ,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,		30		nC
Q_{gs}	Gate-source charge	V_{DS} =400V, V_{GS} =10V, I_{D} =5.5A (note 4,5)		4		
Q_{gd}	Gate-drain charge	(14		

Source to drain diode ratings characteristics

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
Is	Continuous source current	Integral reverse p-n Junction			5.5	Α
I _{SM}	Pulsed source current	diode in the MOSFET			22	Α
V _{SD}	Diode forward voltage drop.	I _S =5.5A, V _{GS} =0V			1.4	V
t _{rr}	Reverse recovery time	I _S =5.5A, V _{GS} =0V,		370		ns
Q _{rr}	Reverse recovery charge	dl _F /dt=100A/us		2.8		uC

. Notes

- Repeatitive rating : pulse width limited by junction temperature.
- L = 15.8mH, I_{AS} = 5.5A, V_{DD} = 50V, R_G=25Ω, Starting T_J = 25°C I_{SD} ≤ 5.5A, di/dt = 100A/us, V_{DD} ≤ BV_{DSS}, Staring T_J =25°C Pulse Test : Pulse Width ≤ 300us, duty cycle ≤ 2%. 2.
- 3.
- 4.
- Essentially independent of operating temperature.

Fig. 1. On-state characteristics

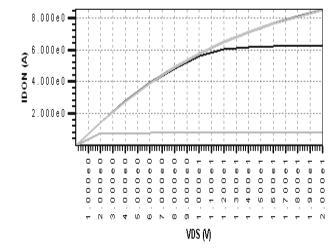


Fig. 2. On-resistance variation vs. drain current and gate voltage

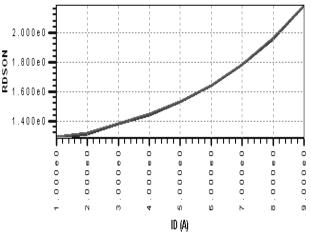


Fig. 3. Gate charge characteristics

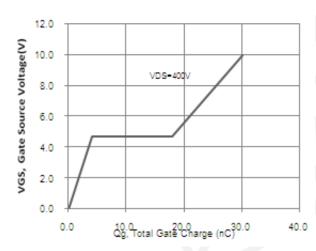


Fig. 4. On state current vs. diode forward voltage

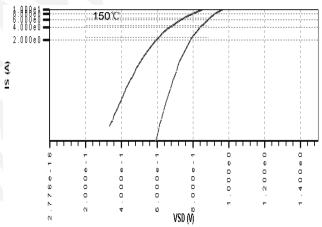


Fig 5. Breakdown Voltage Variation vs. Junction Temperature

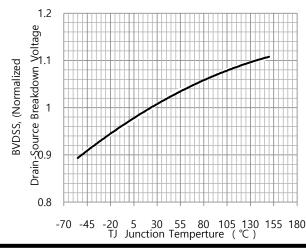


Fig. 6. On resistance variation vs. junction temperature

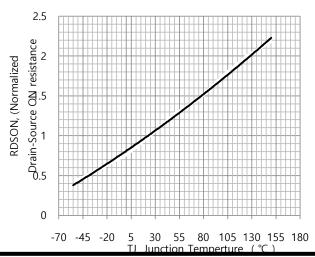


Fig. 7. Maximum safe operating area

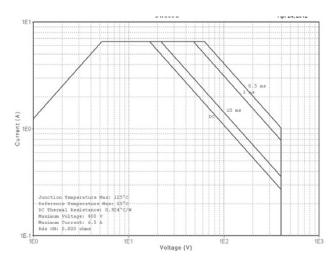


Fig. 8. Transient thermal response curve

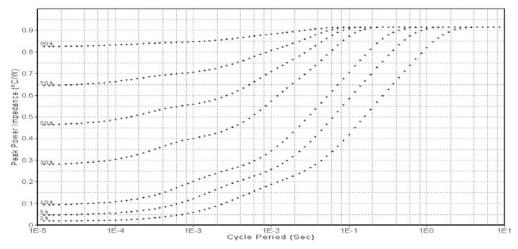


Fig. 9. Gate charge test circuit & waveform

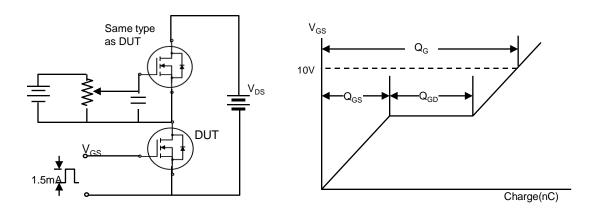


Fig. 10. Switching time test circuit & waveform

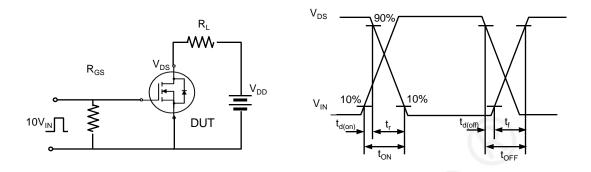


Fig. 14. Unclamped Inductive switching test circuit & waveform

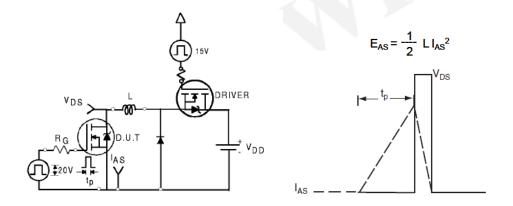
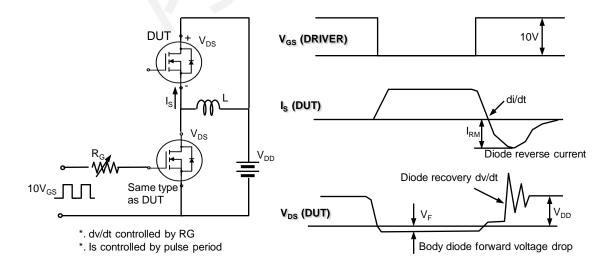


Fig. 15. Peak diode recovery dv/dt test circuit & waveform





DISCLAIMER

- * All the data&curve in this document was tested in XI'AN SEMIPOWER TESTING & APPLICATION CENTER.
- * This product has passed the PCT,TC,HTRB,HTGB,HAST,PC and Solderdunk reliability testing.
- * Qualification standards can also be found on the Web site (http://www.semipower.com.cn)
- * Suggestions for improvement are appreciated, Please send your suggestions to **samwin@samwinsemi.com**